4th International Conference on Accelerated Life Testing and Degradation Models: June 4-6, 2012. INSA Rennes, France

PROGRAM

DAY 1: Monday 4, June 2012

9h00-10h00	Registration – Coffee ***(building 4: ground floor)***		
10h00-10h30	Conference opening ***(Hall D, building 4)***		
10h30-11h15	Plenary speaker ***(Hall D, building 4)***	**W. Meeker**	Methods for planning accelerated repeated measures degradation tests
11h15-12h00	Plenary speaker ***(Hall D, building 4)***	**C. Huber**	Acceleration of time to onset of a disease due to professional exposure. Application to asbestos
12h00-13h30	Lunch ***(INSA restaurant)***		
13h30-14h15	Software exhibition by JMP ***(Hall GCU, building 7)***	**Baudet F.** and **Nedbal V.**	
14h15-15h00	Plenary speaker ***(Hall GCU, building 7)***	**P. Dersin**	Predicting electronic devices' variable failure intensity
15h00-15h45	Plenary speaker ***(Hall GCU, building 7)***	**W. Kahle**	Optimal preventive maintenance in degradation processes
15h45-16h15	Coffee break ***(entrance of Hall GCU, building 7)***		
16h15-17h15	Session 1: Proportional hazards models and related methods ***(Hall GCU, building 7)***		
	1. **Mezaouer A.**: *A nonparametric test for comparing treatments with missing data and dependent censoring* 2. **Grama I.**: *A semi-parametric model for prediction in survival analysis* 3. **Oueslati A.**: *Proportional hazard regression with multiple change-point detection*		

17h15-17h25	Break	
17h25-18h45	Parallel session 2: Accelerated life methods ***(Hall GCU, building 7)***	Parallel session 3: Degradation data analysis ***(Hall André Bonnin, building 5)***
	1. **Hove H.**: *Contributions to Accelerated Reliability Testing* 2. **Saintis L.**: *Optimal accelerated test plan: optimization procedure using Genetic algorithm.* 3. **Haghighi F.**: *Accelerated life test planning with independent competing risks and degradation measurements* 4. **Beaumont P.**: *Analysis of different estimation methods from an accelerated test plan. Application on the fatigue performance of chassis parts*	1. **Freitas M.**: *Application of the Probability Integral Transformation to degradation data analysis* 2. **Pulcini G.**: *A competing risks model with degradation phenomena and catastrophic failures* 3. **Serban N.**: *Residual lifetime prediction using a flexible Bayesian time warping approach* 4. **Paroissin C.**: *Failure time for the Wiener process: first- or last-passage time?*

DAY 2: Tuesday 5, June 2012

8h30-9h15	Plenary speaker ***(Hall GCU, building 7)***	**E.A. Elsayed**	Stress sequence-dependent reliability prediction models
9h15-10h00	Plenary speaker ***(Hall GCU, building 7)***	**K. Suzuki**	Optimal maintenance using advanced quality and reliability information system considering seasonal effects
10h00-10h30	Coffee break ***(entrance of Hall GCU, building 7)***		
10h30-11h50	Parallel session 4: Reliability models ***(Hall GCU, building 7)***		Parallel session 5: Reliability and degradation modeling and estimation ***(Hall André Bonnin, building 5)***
	1. **Gaudoin O.**: *Bayesian Analysis of ARA Imperfect Repair Models* 2. **Medjoudj R.**: *Reliability based preventive maintenance of oil circuit breaker subject to competing failure processes* 3. **Porat Z.**: *Survivability and Life Expectancy Modeling for Items Subjected to Complex Life Profile* 4. **Gotwalt C.**: *Forecasting PV Power Output Using a Two Component Nonlinear Model*		1. **Besnier J.-F.**: *Random failure rate database building on the basis of field data* 2. **de Reffye J.**: *RELSYS methodology and software for calculating the reliability parameters by the scientific calculation* 3. **Chaloupka J.**: *Accelerated tests of electronic parts used in military vehicles* 4. **Hersant J.**: *Wear degradation modeling by stochastic process: physic, modeling and analysis*
12h00-13h30	Lunch ***(INSA restaurant)***		
14h00-22h00	Trip to the Mont-Saint-Michel and Conference Dinner		

DAY 3: Wednesday 6, June 2012

9h00-9h45	Plenary speaker ***(Hall GCU, building 7)***	**N. Limnios**	Dynamical Systems in semi-Markov Media for Structural Reliability Estimation
9h45-10h30	Plenary speaker ***(Hall GCU, building 7)***	**C. Paroissin**	About non-homogeneous gamma process
10h30-11h00	Coffee break ***(entrance of Hall GCU, building 7)***		
11h00-12h00	Session 6: Applications of reliability models and methods ***(Hall GCU, building 7)***		
	1. **Guerin F.**: *Analysis of integrated circuit reliability for oxide breakdown at design time* 2. **Medjoudj R.**: *Degradation modeling and reliability evaluation of photovoltaic module* 3. **Tounsi M.**: *PWM power cycling test for IGBT modules operating at high ambient temperature*		
12h00-13h30	Lunch ***(INSA restaurant)***		
13h30-14h15	Plenary speaker ***(Hall GCU, building 7)***	**M. Nikulin**	The Cox or proportional hazards model and its role in Accelerated Life Testing
14h15-14h45	Conference closure		